# Dual General Purpose Transistors

# **NPN Duals**

These transistors are designed for general purpose amplifier applications. They are housed in the SOT-363/SC-88 which is designed for low power surface mount applications.

• Device Marking:

BC846BDW1T1 = 1BBC847BDW1T1 = 1FBC847CDW1T1 = 1GBC848BDW1T1 = 1KBC848CDW1T1 = 1L

## MAXIMUM RATINGS

Rating	Symbol	BC846	BC847	BC848	Unit
Collector–Emitter Voltage	VCEO	65	45	30	V
Collector-Base Voltage	VCBO	80	50	30	V
Emitter-Base Voltage	VEBO	6.0	6.0	5.0	V
Collector Current – Continuous	IC	100	100	100	mAdc

# THERMAL CHARACTERISTICS

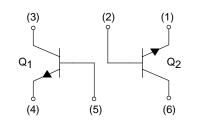
Characteristic	Symbol	Мах	Unit
Total Device Dissipation Per Device FR–5 Board (Note 1.) T <sub>A</sub> = 25°C Derate Above 25°C	PD	380 250	mW mW/∘C
Derate Above 25°C		3.0	mvv/°C
Thermal Resistance, Junction to Ambient	$R_{\theta}JA$	328	°C/W
Junction and Storage Temperature Range	ТЈ, Т <sub>stg</sub>	-55 to +150	°C

1. FR-5 = 1.0 x 0.75 x 0.062 in



# ON Semiconductor™

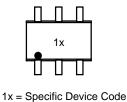
http://onsemi.com





SOT-363 CASE 419B STYLE 1

# **DEVICE MARKING**



x = B, F, G, K, L

# ORDERING INFORMATION

Device	Package	Shipping
BC846BDW1T1	SOT-363	3000 Units/Reel
BC847BDW1T1	SOT-363	3000 Units/Reel
BC847CDW1T1	SOT-363	3000 Units/Reel
BC848BDW1T1	SOT-363	3000 Units/Reel
BC848CDW1T1	SOT-363	3000 Units/Reel

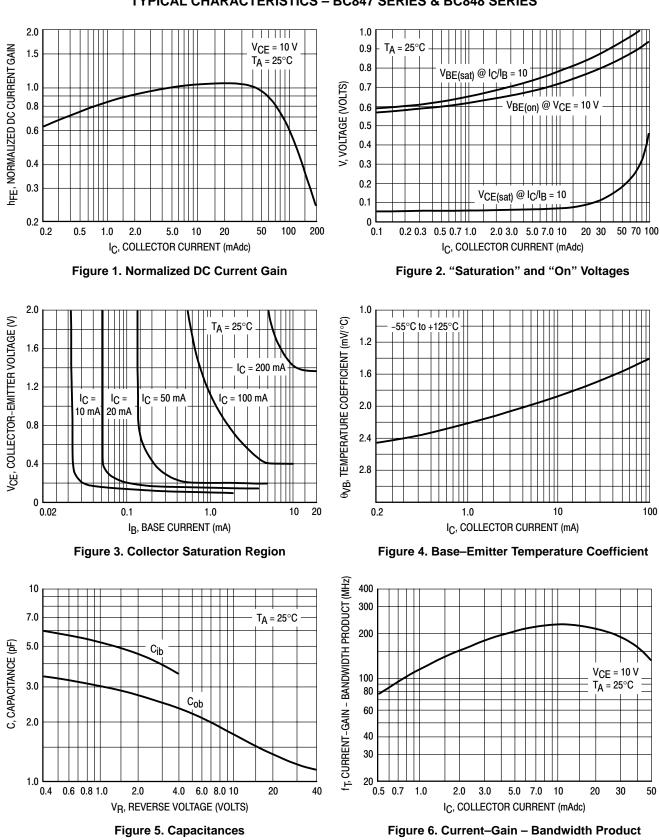
$\begin{array}{c} \mbox{OFF CHARACTERISTICS} \\ \hline Collector-Emitter Breakdown Voltage \\ (I_C = 10 \text{ mA}) & BC846 \text{ Ser} \\ BC847 \text{ Ser} \\ BC848 \text{ Ser} \\ \hline Collector-Emitter Breakdown Voltage \\ (I_C = 10 \ \mu\text{A}, \ V_{EB} = 0) & BC846 \text{ Ser} \\ BC847 \text{ Ser} \\ \hline BC847 \text{ Ser} \\ BC847 \text{ Ser} \\ \hline BC847 \text{ Ser} \\ \hline \end{array}$	ies ies V(BR)CES	65 45 30	_ _ _	-	V
$(I_{C} = 10 \text{ mA}) \\ BC846 \text{ Ser} \\ BC847 \text{ Ser} \\ BC848 \text{ Ser} \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ BC846 \text{ Ser} \\ BC846 \text{ Ser} \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ BC846 \text{ Ser} \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ BC846 \text{ Ser} \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ BC846 \text{ Ser} \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ Collector-Emitter Breakdown Voltage \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ (I_{C} = 10 \ \mu\text{A}, \$	ies ies V(BR)CES	45	_ _ _		V
$\begin{array}{c} BC847 \ Ser\\ BC848 \ Ser\\ \hline \\ Collector-Emitter \ Breakdown \ Voltage\\ (I_C = 10 \ \mu\text{A}, \ V_{EB} = 0) \\ \end{array} \\ \begin{array}{c} BC846 \ Ser\\ BC846 \ Ser\\ \hline \\ \end{array}$	ies ies V(BR)CES	45	_ _ _	-	
$\begin{tabular}{lllllllllllllllllllllllllllllllllll$	V(BR)CES	-		_	
Collector–Emitter Breakdown Voltage ( $I_C = 10 \ \mu A, V_{EB} = 0$ ) BC846 Ser	V <sub>(BR)</sub> CES	30	-	_	1
$(I_{C} = 10 \ \mu\text{A}, \ V_{EB} = 0)$ BC846 Ser	V(BR)CES			1 -	
	(=, = = =				V
BC847 Ser	les	80	-	-	
	ies	50	-	-	
BC848 Ser	ies	30	-	-	
Collector–Base Breakdown Voltage	V(BR)CBO				V
(I <sub>C</sub> = 10 μA) BC846 Ser	ies	80	-	-	
BC847 Ser	ies	50	-	-	
BC848 Ser	ies	30	-	-	
Emitter–Base Breakdown Voltage	V <sub>(BR)EBO</sub>				V
(I <sub>E</sub> = 1.0 μA) BC846 Ser	ies	6.0	-	-	
BC847 Ser	ies	6.0	-	-	
BC848 Ser	ies	5.0	-	-	
Collector Cutoff Current (V <sub>CB</sub> = 30 V)	ICBO	_	-	15	nA
$(V_{CB} = 30 \text{ V}, \text{T}_{A} = 150^{\circ}\text{C})$		-	-	5.0	μA
ON CHARACTERISTICS					

## **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise noted)

DC Current Gain ( $I_C = 10 \ \mu A, V_{CE} = 5.0 \ V$ ) BC846B, BC847B, BC848B		hFE	-	150	_	-
BC847C, BC848C (I <sub>C</sub> = 2.0 mA, V <sub>CE</sub> = 5.0 V) BC846B, BC847B, BC848B BC847C, BC848C			- 200 420	270 290 520	- 450 800	
Collector–Emitter Saturation Voltage ( $I_C = 10 \text{ mA}$ , $I_B = 0.5 \text{ mA}$ ) ( $I_C = 100 \text{ mA}$ , $I_B = 5.0 \text{ mA}$ )		V <sub>CE(sat)</sub>		-	0.25 0.6	V
Base–Emitter Saturation Voltage (I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0.5 mA) (I <sub>C</sub> = 100 mA, I <sub>B</sub> = 5.0 mA)		VBE(sat)	_ _	0.7 0.9		V
Base–Emitter Voltage (I <sub>C</sub> = 2.0 mA, V <sub>CE</sub> = 5.0 V) (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 5.0 V)		V <sub>BE(on)</sub>	580 -	660 -	700 770	mV

#### SMALL-SIGNAL CHARACTERISTICS

Current–Gain – Bandwidth Product (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 5.0 Vdc, f = 100 MHz)	fΤ	100	_	_	MHz
Output Capacitance ( $V_{CB} = 10 \text{ V}, f = 1.0 \text{ MHz}$ )	Cobo	-	-	4.5	pF
Noise Figure (I <sub>C</sub> = 0.2 mA, V <sub>CE</sub> = 5.0 Vdc, R <sub>S</sub> = 2.0 k $\Omega$ ,f = 1.0 kHz, BW = 200 Hz)	NF	_	-	10	dB



# **TYPICAL CHARACTERISTICS – BC847 SERIES & BC848 SERIES**

#### 1.0 hFE, DC CURRENT GAIN (NORMALIZED) T<sub>A</sub> = 25°C = 5 V CF ++++ 0.8 \_ = 25°C TΑ V<sub>BE(sat)</sub> @ I<sub>C</sub>/I<sub>B</sub> = 10 V, VOLTAGE (VOLTS) 2.0 ΠÌ 0.6 V<sub>BE</sub> @ V<sub>CE</sub> = 5.0 V 1.0 |||||0.4 +++ 0.5 0.2 0.2 V<sub>CE(sat)</sub> @ I<sub>C</sub>/I<sub>B</sub> = 10 0 0.1 0.2 1.0 10 100 0.2 0.5 1.0 2.0 5.0 10 20 50 100 200 IC, COLLECTOR CURRENT (mA) IC, COLLECTOR CURRENT (mA) Figure 7. Normalized DC Current Gain Figure 8. "On" Voltage 2.0 V<sub>CE</sub>, COLLECTOR-EMITTER VOLTAGE (VOLTS) -1.0 ТПП $\theta_{VB},$ TEMPERATURE COEFFICIENT (mV/ $^\circ\text{C})$ ТА = 25 C 1.6 -1.4 100 mA 200 mA 20 mA 50 mA 1.2 -1.8 $\theta_{VB}$ for $V_{BE}$ -55°C to 125°C IC = 0.8 -2.2 10 mA 0.4 -2.6 0 -3.0 2.0 0.02 0.05 0.1 0.2 0.5 1.0 2.0 5.0 10 20 0.2 0.5 1.0 5.0 10 20 50 100 200 IB, BASE CURRENT (mA) IC, COLLECTOR CURRENT (mA) **Figure 9. Collector Saturation Region** Figure 10. Base–Emitter Temperature Coefficient 40 $f_{\rm T}, {\tt CURRENT-GAIN}$ – BANDWIDTH PRODUCT = 25°C = 5 V TA VCF 500 T<sub>A</sub> = 25°C 20 C, CAPACITANCE (pF) C<sub>ib</sub> 200 10 100 6.0 50 Cob 4.0 20 2.0 0.1 0.2 2.0 20 5.0 10 50 100 0.5 1.0 5.0 10 50 100 1.0 VR, REVERSE VOLTAGE (VOLTS) IC, COLLECTOR CURRENT (mA)

#### **TYPICAL CHARACTERISTICS – BC846 SERIES**

Figure 11. Capacitance

Figure 12. Current–Gain – Bandwidth Product

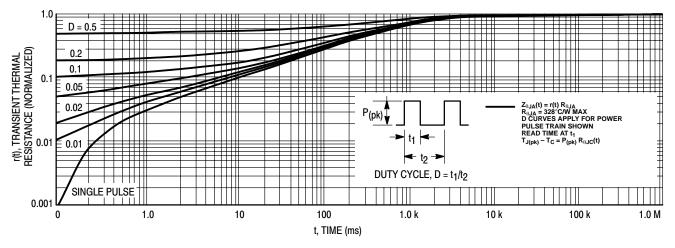


Figure 13. Thermal Response

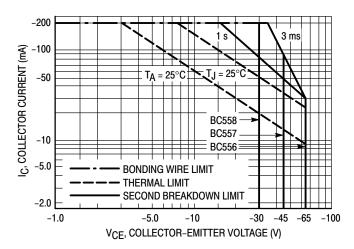


Figure 14. Active Region Safe Operating Area

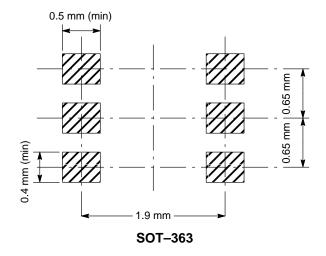
The safe operating area curves indicate  $I_C-V_{CE}$  limits of the transistor that must be observed for reliable operation. Collector load lines for specific circuits must fall below the limits indicated by the applicable curve.

The data of Figure 14 is based upon  $T_{J(pk)} = 150^{\circ}C$ ;  $T_C$  or  $T_A$  is variable depending upon conditions. Pulse curves are valid for duty cycles to 10% provided  $T_{J(pk)} \le 150^{\circ}C$ .  $T_{J(pk)}$  may be calculated from the data in Figure 13. At high case or ambient temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by the secondary breakdown.

# INFORMATION FOR USING THE SOT-363 SURFACE MOUNT PACKAGE MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



#### SOT-363 POWER DISSIPATION

The power dissipation of the SOT–363 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet for the SOT–363 package,  $P_D$  can be calculated as follows:

$$P_{D} = \frac{T_{J(max)} - T_{A}}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of 25°C, one can calculate the power dissipation of the device which in this case is 150 milliwatts.

$$P_{D} = \frac{150^{\circ}C - 25^{\circ}C}{833^{\circ}C/W} = 150 \text{ milliwatts}$$

The 833°C/W for the SOT–363 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 150 milliwatts. There are other alternatives to achieving higher power dissipation from the SOT–363 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad<sup>™</sup>. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

#### SOLDERING PRECAUTIONS

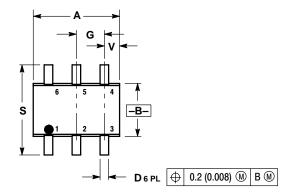
The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.\*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

\* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

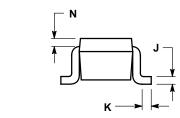
# PACKAGE DIMENSIONS

SOT-363 CASE 419B-01 **ISSUE G** 



С

н



NOTES: DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.071	0.087	1.80	2.20	
В	0.045	0.053	1.15	1.35	
С	0.031	0.043	0.80	1.10	
D	0.004	0.012	0.10	0.30	
G	0.026	0.026 BSC		BSC	
н		0.004		0.10	
J	0.004	0.010	0.10	0.25	
К	0.004	0.012	0.10	0.30	
Ν	0.008	B REF	0.20	REF	
S	0.079	0.087	2.00	2.20	
V	0.012	0.016	0.30	0.40	

STYLE 1: PIN 1. EMITTER 2 2. BASE 2 3. COLLECTOR 1 4. EMITTER 1 5. BASE 1 6. COLLECTOR 2

Thermal Clad is a trademark of the Bergquist Company.

**ON Semiconductor** and without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer.

#### PUBLICATION ORDERING INFORMATION

#### Literature Fulfillment:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA **Phone:** 303–675–2175 or 800–344–3860 Toll Free USA/Canada **Fax:** 303–675–2176 or 800–344–3867 Toll Free USA/Canada

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

JAPAN: ON Semiconductor, Japan Customer Focus Center 4–32–1 Nishi–Gotanda, Shinagawa–ku, Tokyo, Japan 141–0031 Phone: 81–3–5740–2700 Email: r14525@onsemi.com

ON Semiconductor Website: http://onsemi.com

For additional information, please contact your local Sales Representative.

Email: ONlit@hibbertco.com